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Date: 19-Aug-2021

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NXP SEMICONDUCTORS

HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

The following sample(s) was/were submitted and identified by/on behalf of the applicant as: Sample Submitted By NXP SEMICONDUCTORS : Sample Name OAK HILL BARE WAFER _____ Sample Receiving Date : 06-Aug-2021 Testing Period 06-Aug-2021 to 13-Aug-2021 : **Test Requested** (1) As specified by client, with reference to RoHS 2011/65/EU Annex II and amending : Directive (EU) 2015/863 to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP contents in the submitted sample(s). (2) Please refer to next pages for the other item(s). **Test Results** Please refer to following pages. Conclusion (1) Based on the performed tests on submitted sample(s), the test results of : Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP comply with the limits as set by RoHS Directive (EU) 2015/863 amending Annex II to Directive 2011/65/EU.



SGS TAIWAN LTD. Chemical Laboratory-Kaohsiung



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Test Part Description

No.1 : MULTICOLORED WAFER

Test Result(s)

Test Item(s)	Method	Unit	MDL	Result	Limit
				No.1	
Cadmium (Cd) (CAS No.: 7440-43-9)	With reference to IEC 62321-5: 2013,	mg/kg	2	n.d.	100
Lead (Pb) (CAS No.: 7439-92-1)	analysis was performed by ICP-OES.	mg/kg	2	n.d.	1000
Mercury (Hg) (CAS No.: 7439-97-6)	With reference to IEC 62321-4: 2013+	mg/kg	2	n.d.	1000
	AMD1: 2017, analysis was performed				
	by ICP-OES.				
Hexavalent Chromium Cr(VI) (CAS No.:	With reference to IEC 62321-7-2:	mg/kg	8	n.d.	1000
18540-29-9)	2017, analysis was performed by UV-				
	VIS.				
Monobromobiphenyl		mg/kg	5	n.d.	-
Dibromobiphenyl		mg/kg	5	n.d.	-
Tribromobiphenyl		mg/kg	5	n.d.	-
Tetrabromobipenyl		mg/kg	5	n.d.	-
Pentabromobiphenyl		mg/kg	5	n.d.	-
Hexabromobiphenyl		mg/kg	5	n.d.	-
Heptabromobiphenyl		mg/kg	5	n.d.	-
Octabromobiphenyl		mg/kg	5	n.d.	-
Nonabromobiphenyl		mg/kg	5	n.d.	-
Decabromobiphenyl		mg/kg	5	n.d.	-
Sum of PBBs	With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.	mg/kg	-	n.d.	1000
Monobromodiphenyl ether		mg/kg	5	n.d.	-
Dibromodiphenyl ether		mg/kg	5	n.d.	-
Tribromodiphenyl ether		mg/kg	5	n.d.	-
Tetrabromodiphenyl ether		mg/kg	5	n.d.	-
Pentabromodiphenyl ether		mg/kg	5	n.d.	-
Hexabromodiphenyl ether		mg/kg	5	n.d.	-
Heptabromodiphenyl ether		mg/kg	5	n.d.	-
Octabromodiphenyl ether		mg/kg	5	n.d.	-
Nonabromodiphenyl ether]	mg/kg	5	n.d.	-
Decabromodiphenyl ether		mg/kg	5	n.d.	-
Sum of PBDEs		mg/kg	-	n.d.	1000

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Test Item(s)	Method	Unit	MDL	Result	Limit
				No.1	
Butyl benzyl phthalate (BBP) (CAS No.:	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	1000
85-68-7)	analysis was performed by GC/MS.				
Dibutyl phthalate (DBP) (CAS No.: 84-	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	1000
74-2)	analysis was performed by GC/MS.				
Diisobutyl phthalate (DIBP) (CAS No.:	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	1000
84-69-5)	analysis was performed by GC/MS.				
Di-(2-ethylhexyl) phthalate (DEHP)	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	1000
(CAS No.: 117-81-7)	analysis was performed by GC/MS.				
Diisononyl phthalate (DINP) (CAS No.:	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	-
28553-12-0, 68515-48-0)	analysis was performed by GC/MS.				
Diisodecyl phthalate (DIDP) (CAS No.:	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	-
26761-40-0, 68515-49-1)	analysis was performed by GC/MS.				
Di-n-octyl phthalate (DNOP) (CAS No.:	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	-
117-84-0)	analysis was performed by GC/MS.				
Di-n-pentyl phthalate (DNPP) (CAS No.:	With reference to IEC 62321-8: 2017,	mg/kg	50	n.d.	-
131-18-0)	analysis was performed by GC/MS.				
Antimony (Sb) (CAS No.: 7440-36-0)	With reference to US EPA 3052: 1996,	mg/kg	2	n.d.	-
	analysis was performed by ICP-OES.				
Beryllium (Be) (CAS No.: 7440-41-7)	With reference to US EPA 3052: 1996,	mg/kg	2	n.d.	-
	analysis was performed by ICP-OES.				
Arsenic (As) (CAS No.: 7440-38-2)	With reference to US EPA 3052: 1996,	mg/kg	2	n.d.	-
	analysis was performed by ICP-OES.				
Fluorine (F) (CAS No.: 14762-94-8)	With reference to BS EN 14582: 2016,	mg/kg	50	n.d.	-
	analysis was performed by IC.				
Chlorine (Cl) (CAS No.: 22537-15-1)	With reference to BS EN 14582: 2016,	mg/kg	50	n.d.	-
	analysis was performed by IC.				
Bromine (Br) (CAS No.: 10097-32-2)	With reference to BS EN 14582: 2016,	mg/kg	50	n.d.	-
	analysis was performed by IC.				
lodine (I) (CAS No.: 14362-44-8)	With reference to BS EN 14582: 2016,	mg/kg	50	n.d.	-
	analysis was performed by IC.				

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Note :

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. MDL = Method Detection Limit
- 3. n.d. = Not Detected (Less than MDL)
- 4. "-" = Not Regulated
- 5. The statement of compliance conformity is based on comparison of testing results and limits.
- 6. This test report supersedes the previous document bearing the report number EKR21800448, the report EKR21800448 was voided.

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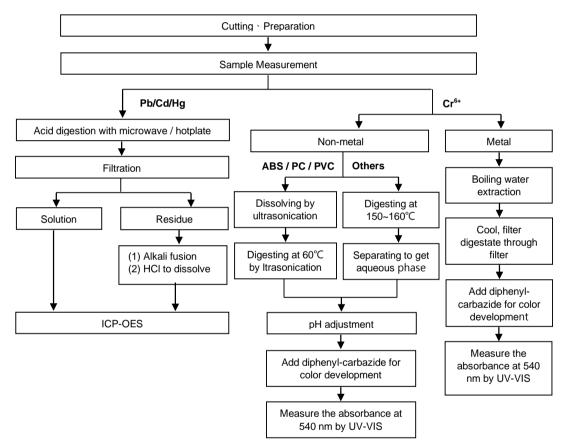
Test Report

HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Heavy Metal

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr6+

test method excluded)



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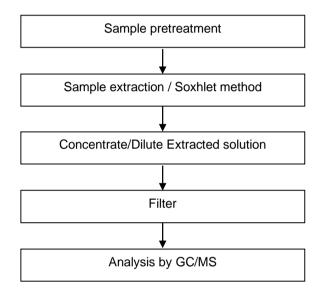
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HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

PBB/PBDE analytical FLOW CHART



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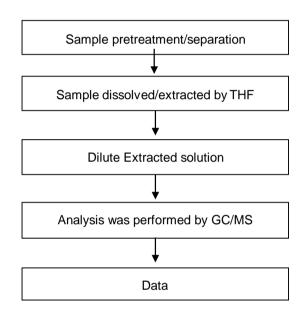
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Analytical flow chart of phthalate content



[Test method: IEC 62321-8]

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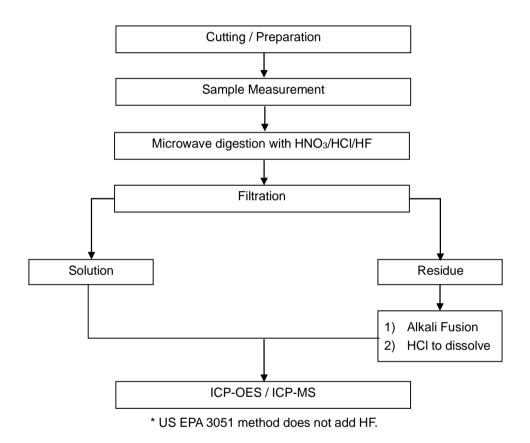
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HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Heavy Metal

These samples were dissolved totally by pre-conditioning method according to below flow chart. [Reference method : US EPA 3051 \ US EPA 3052]



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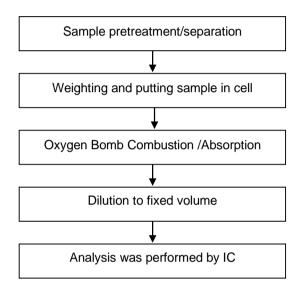
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HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Halogen



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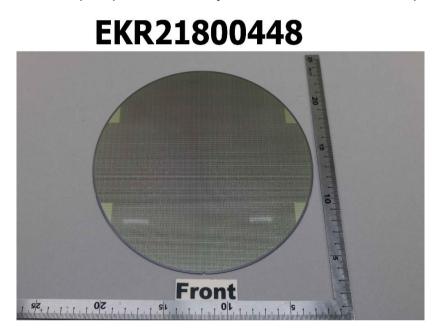
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* The tested sample / part is marked by an arrow if it's shown on the photo. *



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** End of Report **

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